

Search Notes

Applicati n N .

10/724,506

Examiner

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Applicant(s)

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Art Unit

2124

SEARCHED

Class	Subclass	Date	Examiner
708	629-630	4/29/2004	Mai

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Double Patenting Check Data Bases Search (see attached copy)	4/29/2004	Mai